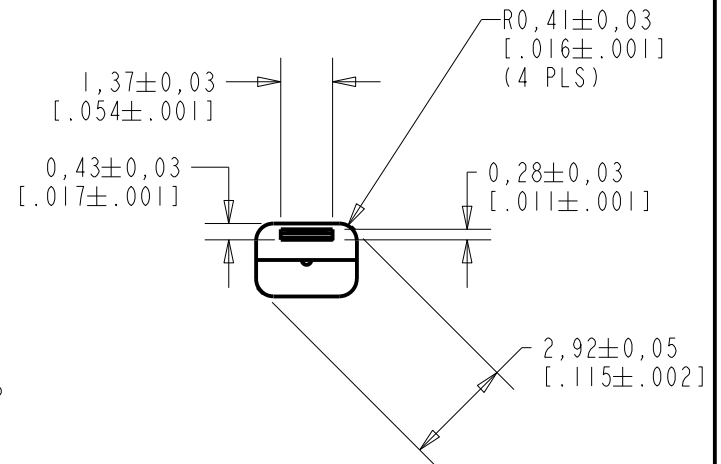
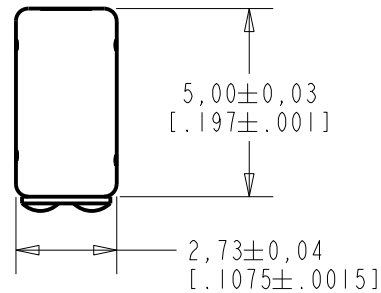


**FK-30040-000**

**SHT 1.1**

NOTES:

- 1 A POSITIVE GOING VOLTAGE AT TERMINAL 2, RELATIVE TO TERMINAL 1, CAUSES A DECREASE IN PRESSURE AT THE SOUND OUTLET.
- 2 LOCATED FROM TWO SURFACES FOR CUSTOMER CONVENIENCE. ONLY APPLICABLE FROM ONE SURFACE, NOT TO BE USED TOGETHER.



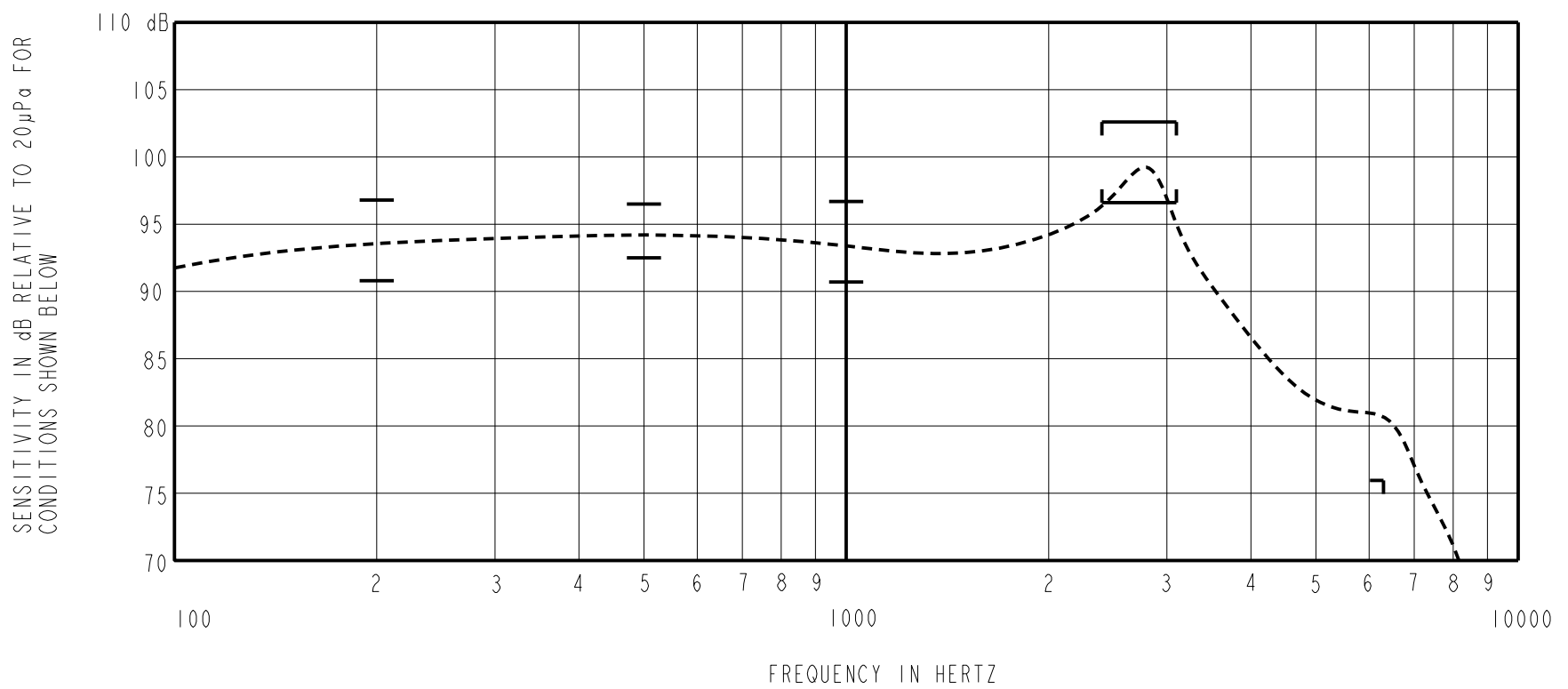
SCALE 2:1

DIMENSIONS IN MILLIMETERS [INCHES]

Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
E	C10111950	12-20-10	<b>Active</b>	<b>E</b>
D	C10110508	11-17-09		

SCALE: <b>5:1</b>		DR. BY	DATE
DO NOT SCALE DRAWING		MMM	8-18-06
TITLE: <b>RECEIVER</b>		CK. BY	DATE
<b>FK-30040-000</b>		GJP	8-18-06
OUTLINE DRAWING		APP. BY	DATE
<b>SHT 1.1</b>		GJP	8-18-06

**KNOWLES ELECTRONICS**  
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**ACOUSTICAL**

SENSITIVITY\*  
DEVICE WILL PRODUCE THE SPL LISTED BELOW UNDER TEST CONDITION IN TABLE 3.  
NOMINAL SENSITIVITY AT 1KHz IS dB RELATIVE TO 20 µPa. ALL OTHER VALUES  
IN dB RELATIVE TO THE SENSITIVITY AT 1KHz.

FREQUENCY (Hz)	MINIMUM	NOMINAL	MAXIMUM
200	-2.9	0.1	+3.1
500	-1.2	0.8	+2.8
1000	-3.0	93.7	+3.0
2400-3100	+2.9	+5.9	+8.9
6300	-17.6	---	---

TABLE 1

TOTAL HARMONIC DISTORTION\*  
DEVICE WILL NOT EXCEED TOTAL HARMONIC DISTORTION LEVELS LISTED BELOW.

FREQUENCY (Hz)	AC DRIVE (V rms)	DC BIAS (V)	LIMIT (%)
900	0.180	0	5
1350	0.360	0	10

TABLE 2

TEST CONDITIONS

NOMINAL SOURCE VOLTAGE	0.180 V rms, 0 mA V DC BIAS
SOURCE IMPEDANCE	<1 Ohm
TUBING	10mm [.394"] LONG, 1mm [.039"] I.D.
COUPLER CAVITY	2 CM <sup>3</sup> , SIMULATED ANSI S3.7 TYPE HA-3 (IEC 60318-5)

TABLE 3

ELECTRICAL

DC RESISTANCE	200 Ohms ± 10%*
IMPEDANCE @ 500 Hz	266 Ohms ± 15%*
IMPEDANCE @ 1kHz	351 Ohms ± 15%*

TABLE 4

ISOLATION: CASE WILL BE ELECTRICALLY ISOLATED FROM THE COIL CIRCUIT.\*

NOTE: SPECIFICATIONS FOLLOWED BY AN ASTERISK(\*) ARE 100% TESTED.

MECHANICAL

PORT LOCATION: 12S  
SOLDER TYPE: SAC305

TEMPERATURE:

OPERATING: SENSITIVITY AT 500 Hz  
WILL NOT VARY MORE THAN  
± 3 dB FROM -17°C TO 63°C.  
STORAGE : -40°C TO 63°C

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Revision	C.O. #	Implementation Date	RELEASE LEVEL	REVISION
E	C10111950	12-20-10	<b>Active</b>	<b>E</b>
D	C10110508	11-17-09		
WHEN TEST LIMITS ARE USED TO ESTABLISH INCOMING INSPECTION ACCEPTANCE/REJECTION CRITERIA, CORRELATION OF TEST EQUIPMENT WITH KNOWLES IS ALSO REQUIRED FOR ELIMINATION OF EQUIPMENT AND TEST METHOD VARIATION			DR. BY	DATE
TITLE: <b>RECEIVER</b> PERFORMANCE SPECIFICATION			MMM	8-18-06
			FK-30040-000	
SHT 2.1			CK. BY	DATE
			GJP	8-18-06
			APP. BY	DATE
			GJP	8-18-06